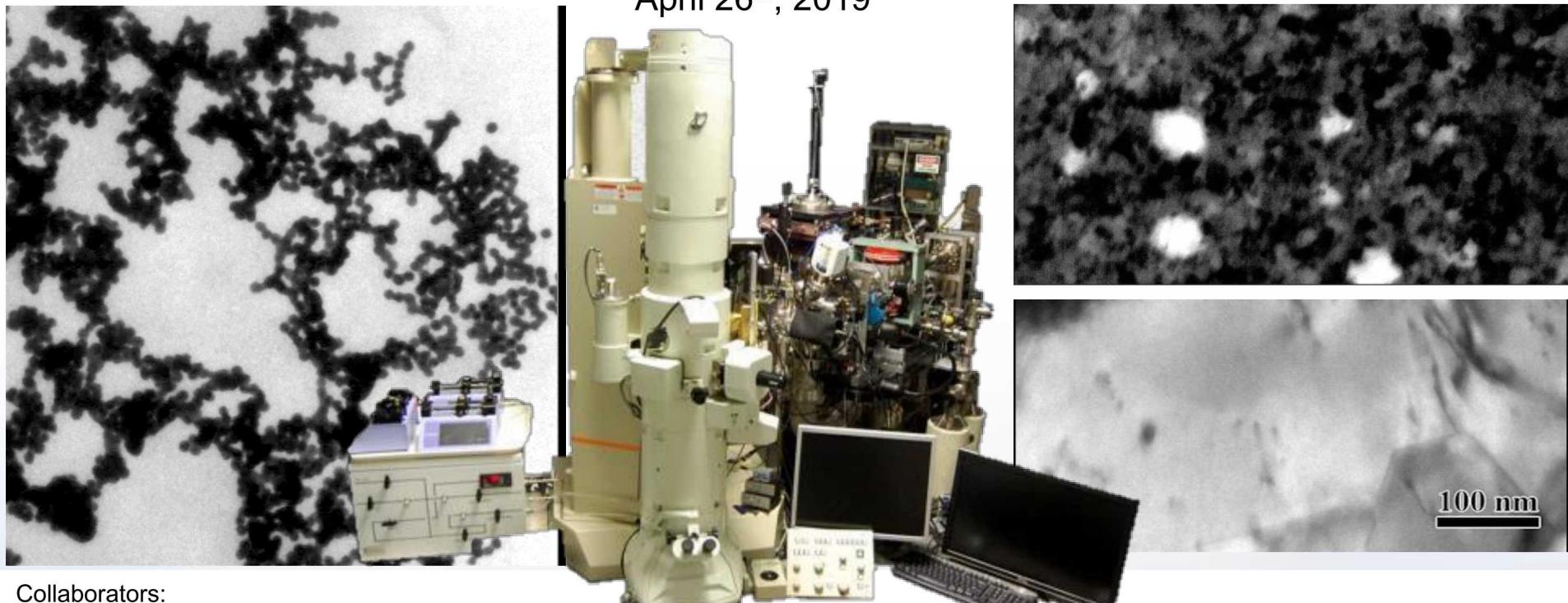


Exploring Extreme Environments with Adequate Temporal Resolution

K. Hattar

Sandia National Laboratories

April 26th, 2019



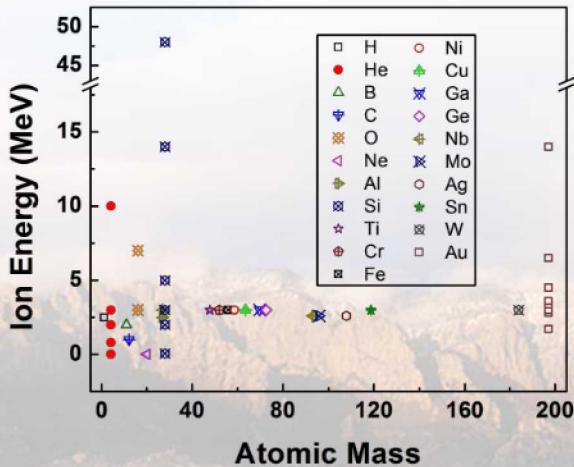
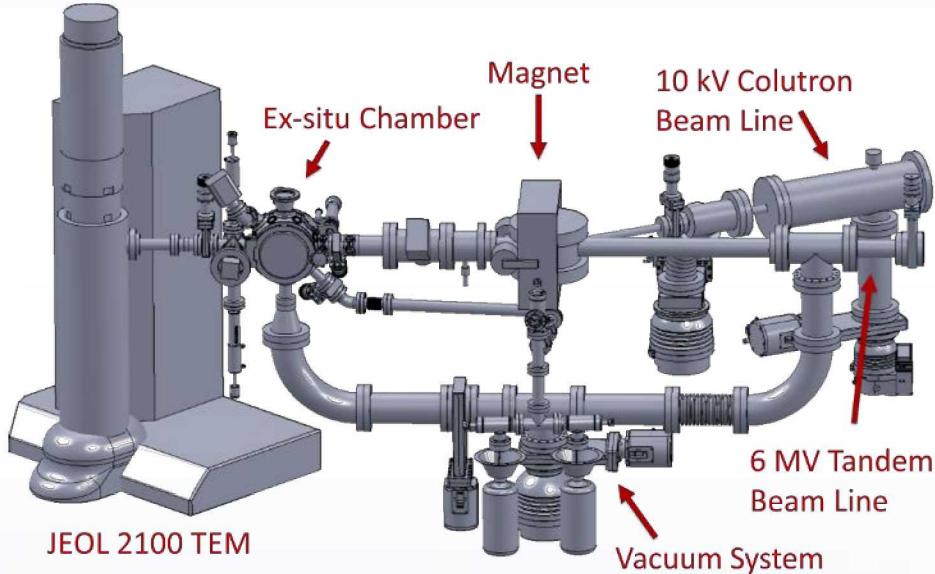
Collaborators:

- D.L. Buller, D.C. Bufford, S.H. Pratt, T.J. Boyle, B.A. Hernandez-Sanchez, S.J. Blair, B. Muntifering, C. Chisholm, P. Hosemann, A. Minor, J. A. Hinks, F. Hibberd, A. Ilinov, D. C. Bufford, F. Djurabekova, G. Greaves, A. Kuronen, S. E. Donnelly, K. Nordlund, F. Abdeljawad, S.M. Foiles, J. Qu, C. Taylor, J. Sugar, P. Price, C.M. Barr, D. Adams, M. Abere, L. Treadwell, A. Cook, A. Monterrosa, IDES Inc, J. Sharon, B. L. Boyce, C. Chisholm, H. Bei, E.P. George, W. Mook, Hysitron Inc., G.S. Jawaharam, S. Dillon, R.S. Averback, N. Heckman, J. Carroll, S. Briggs, E. Carnes, J. Brinker, D. Sasaki, T. Nenoff, B.G. Clark, P.J. Cappillino, B.W. Jacobs, M.A. Hekmaty, D.B. Robinson, L.R. Parent, I. Arslan, & Protochips, Inc.

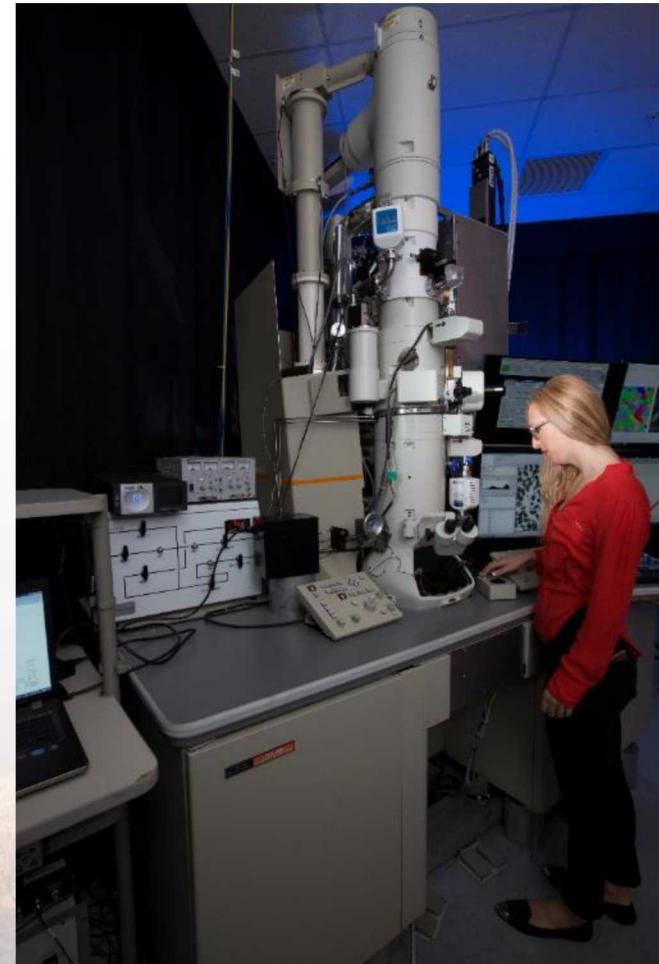
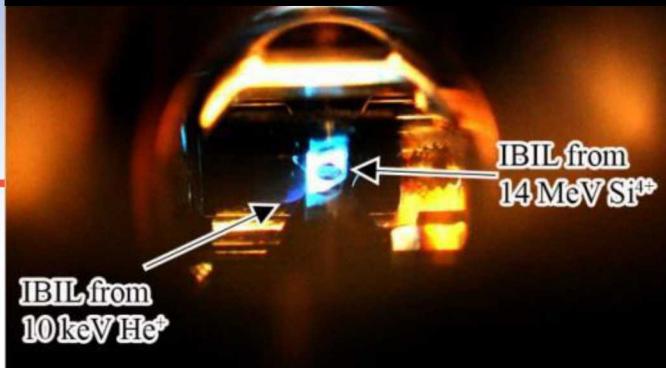
Sandia's Concurrent *In situ* Ion Irradiation TEM Facility

Collaborator: D.L. Buller

10 kV Colutron - 200 kV TEM - 6 MV Tandem



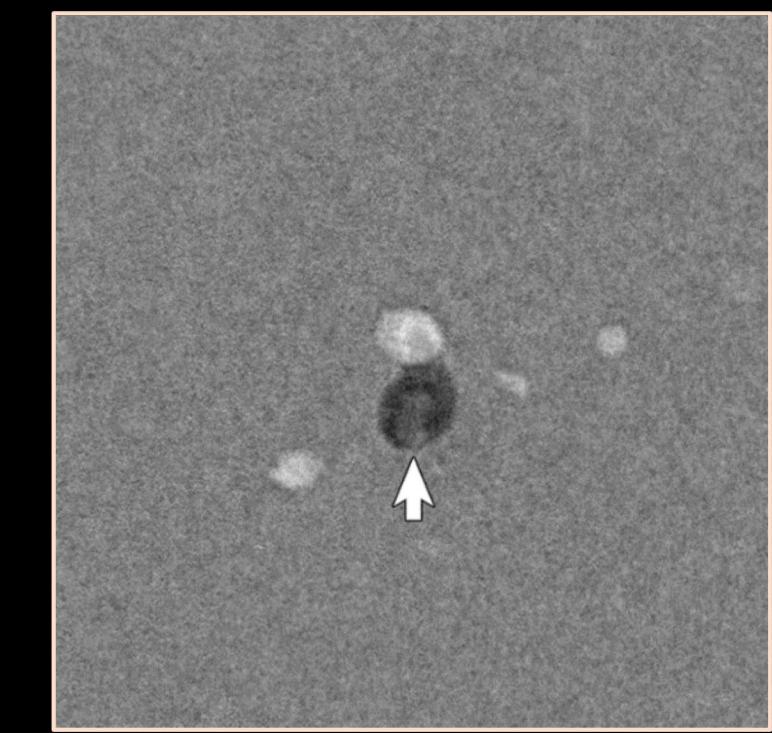
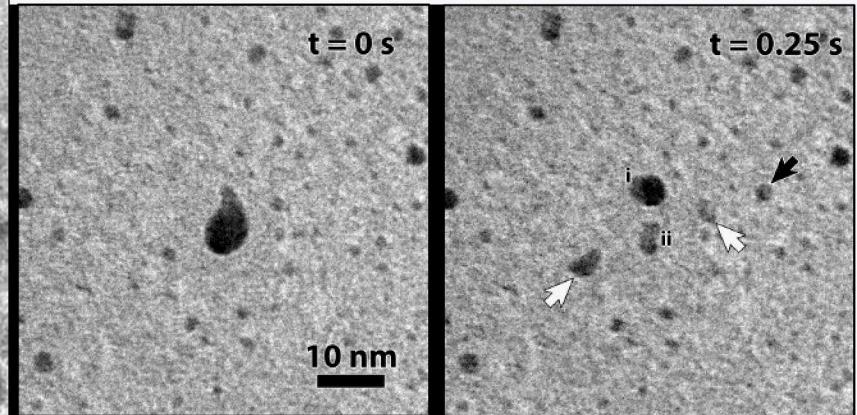
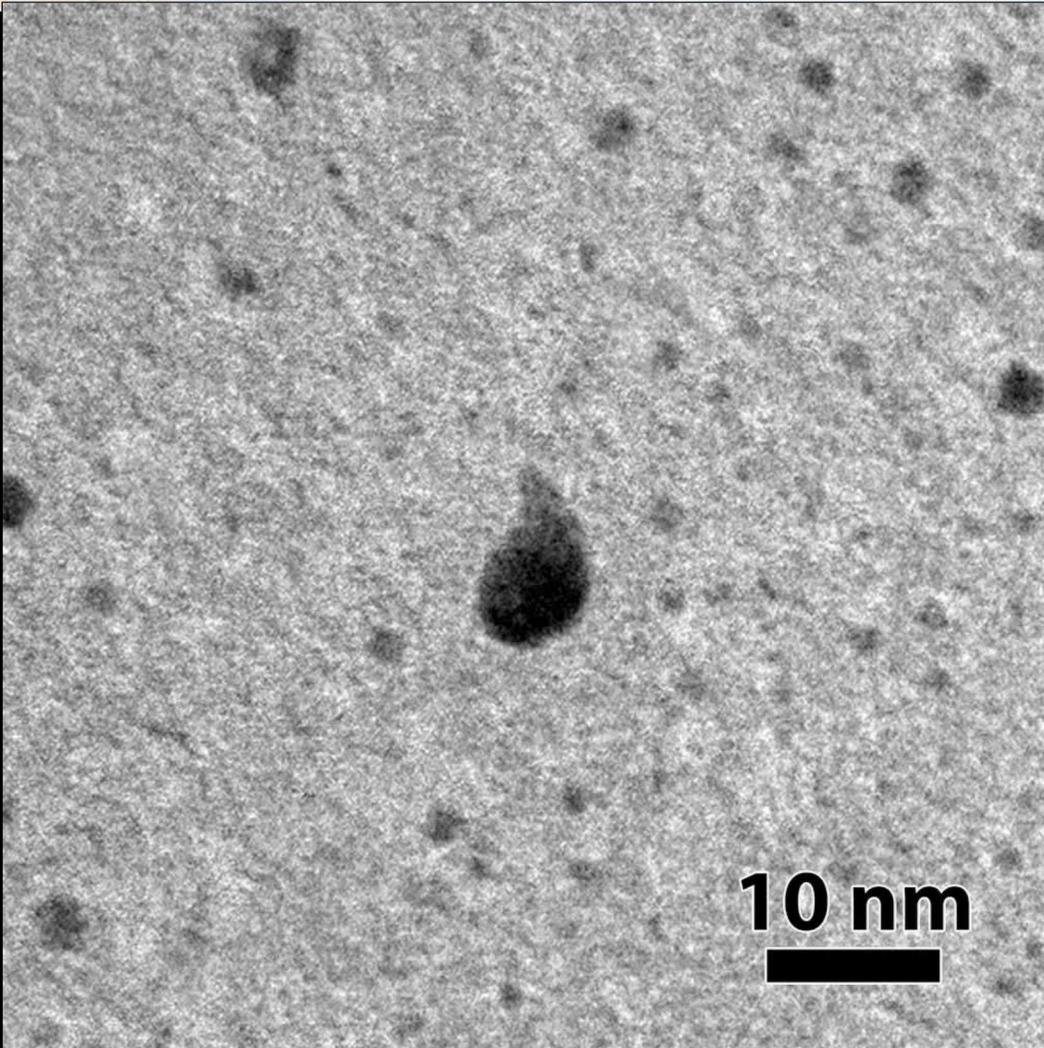
IBIL from a quartz stage inside the TEM





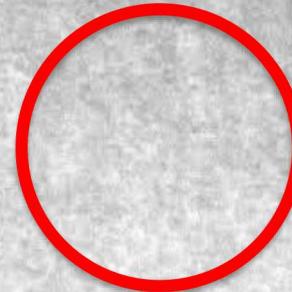
Single Ion Strikes: 46 keV Au¹⁺ ions into 5 nm Au nanoparticles

Collaborator: D.C. Bufford



Motivation: In-Situ Single Ion Strikes in Si

30 nm



difference
image

- 1.7 MeV Au into single crystal Si
- Single ion strikes can be observed in semiconductors
- Non-symmetric structure in contrast to the spherical approximation

Can we go beyond this to observe:

- Important aspects of structural evolution (ns to hrs.)?
- Evolution in more complex systems (GaAs)?
- Directly correlate it to key model parameters?



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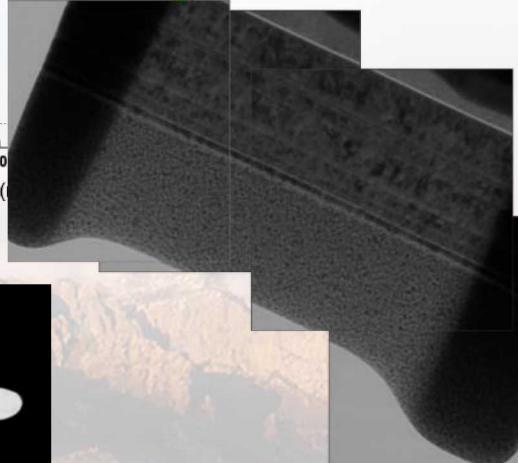
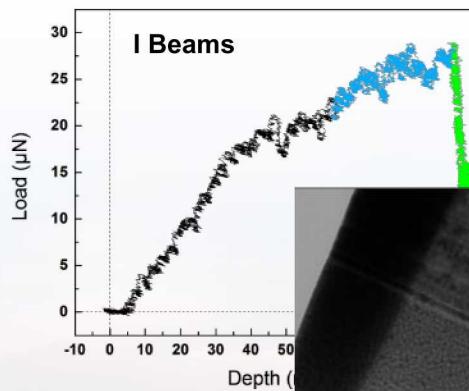
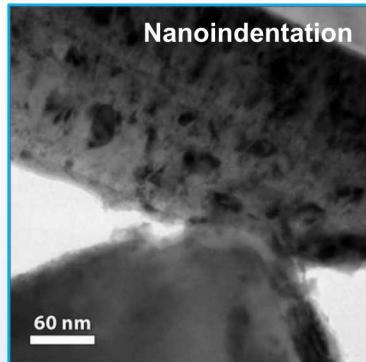
In situ Quantitative Mechanical Testing

Contributors: J. Sharon, B. L. Boyce, C. Chisholm, H. Bei, E.P. George, P. Hosemann, A.M. Minor, & Hysitron Inc.



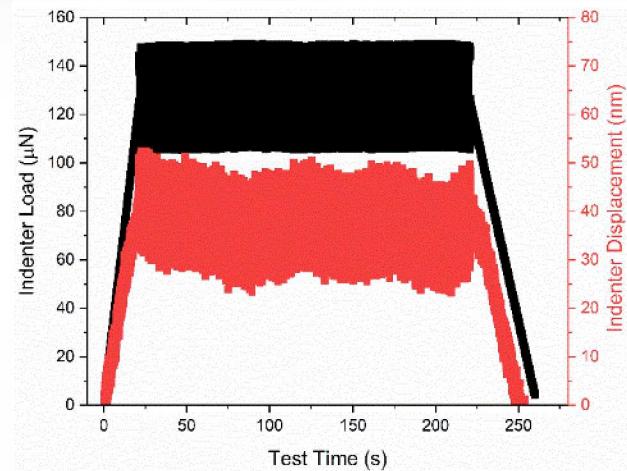
Hysitron PI95 *In Situ* Nanoindentation TEM Holder

- Sub nanometer displacement resolution
- Quantitative force information with μN resolution
- **Concurrent real-time imaging by TEM**



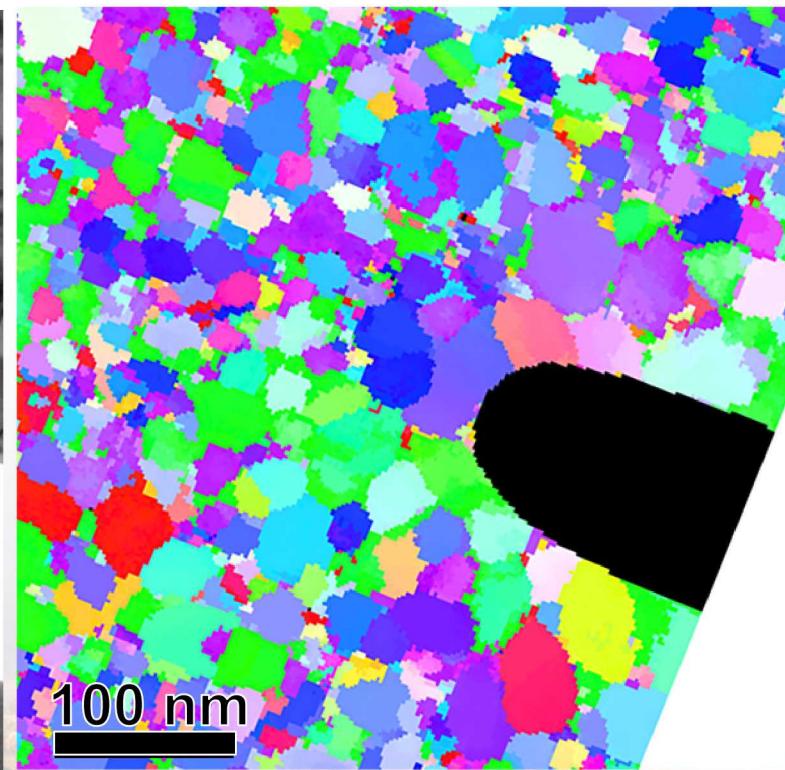
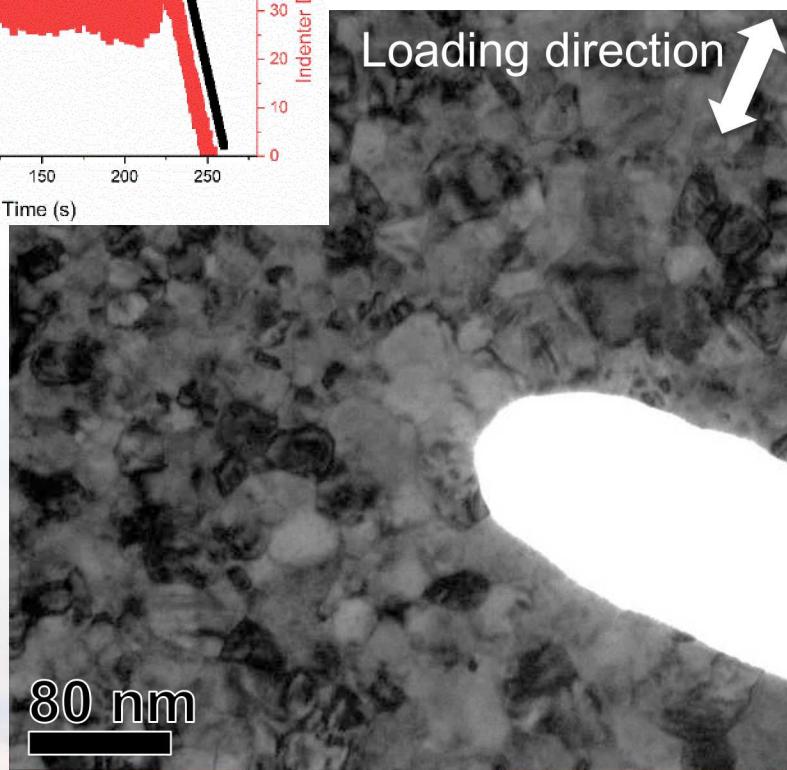
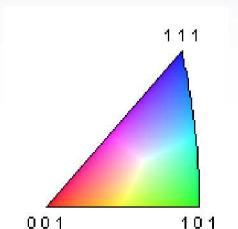
Cyclic Loading Coupled with ACOM

Collaborators: C. Barr & W. Mook



Mean load (P_{mean}) = 135 μN

Amplitude load (P_{amp}) = 35 μN



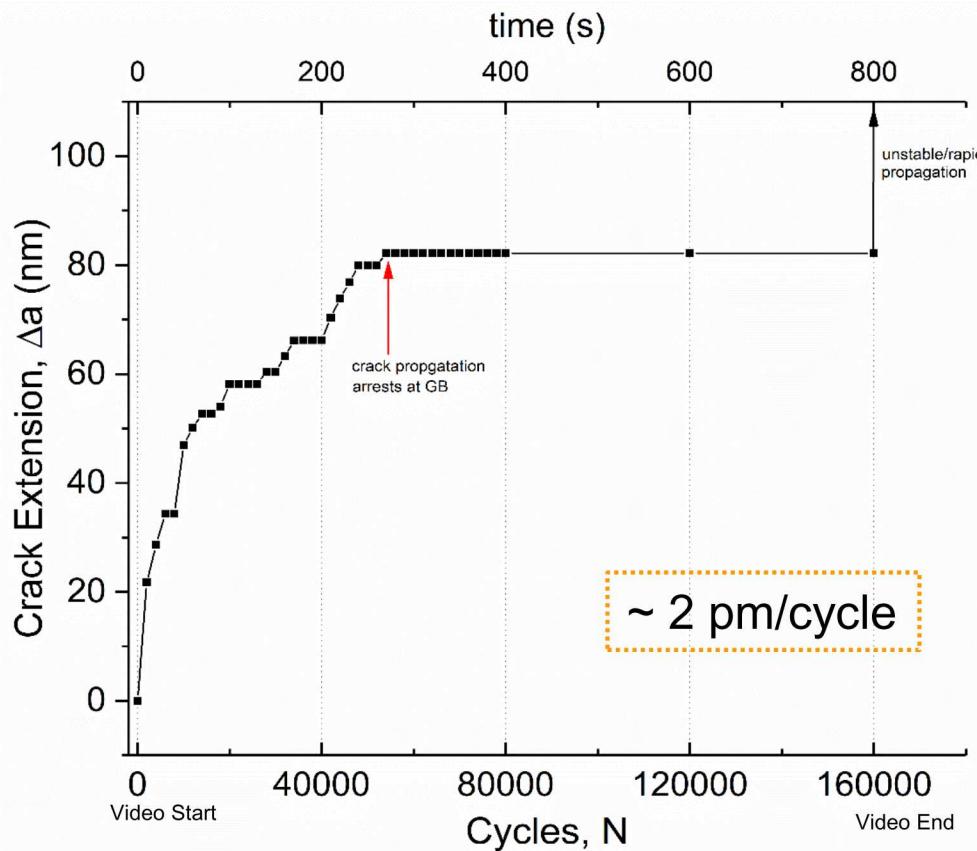
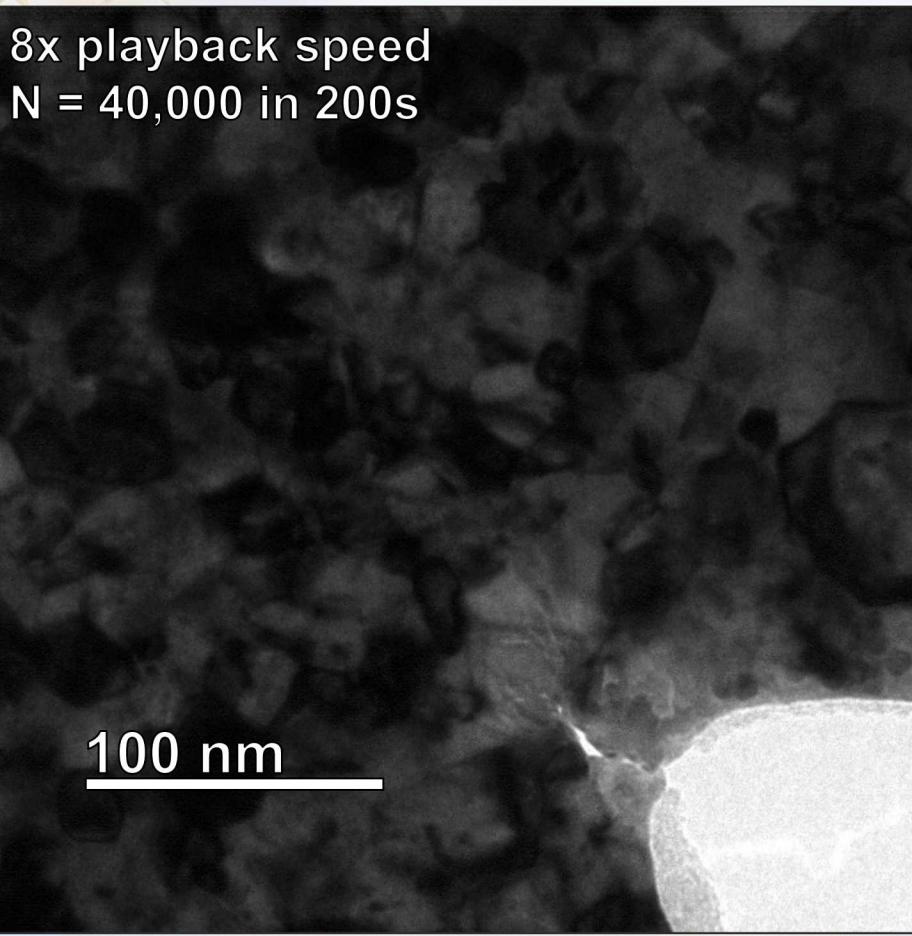
Orientation maps pre-, intermediate, and post- in-situ mechanical test can assist in deconvoluting possible mechanisms during cyclic loading

Cyclic Loading: Complex Crack Propagation

Collaborators: C. Barr & W. Mook

8x playback speed
N = 40,000 in 200s

100 nm



- Mean load: 135 μN ; Amplitude load: 35 μN
- 200 Hz, 200s test (15 fps 1k x 1k camera)

- $\text{da/dN} = 1.7 \times 10^{12} \text{ m/cycle}$
- Non-linear crack extension rate
- Crack propagation path changes “direction”



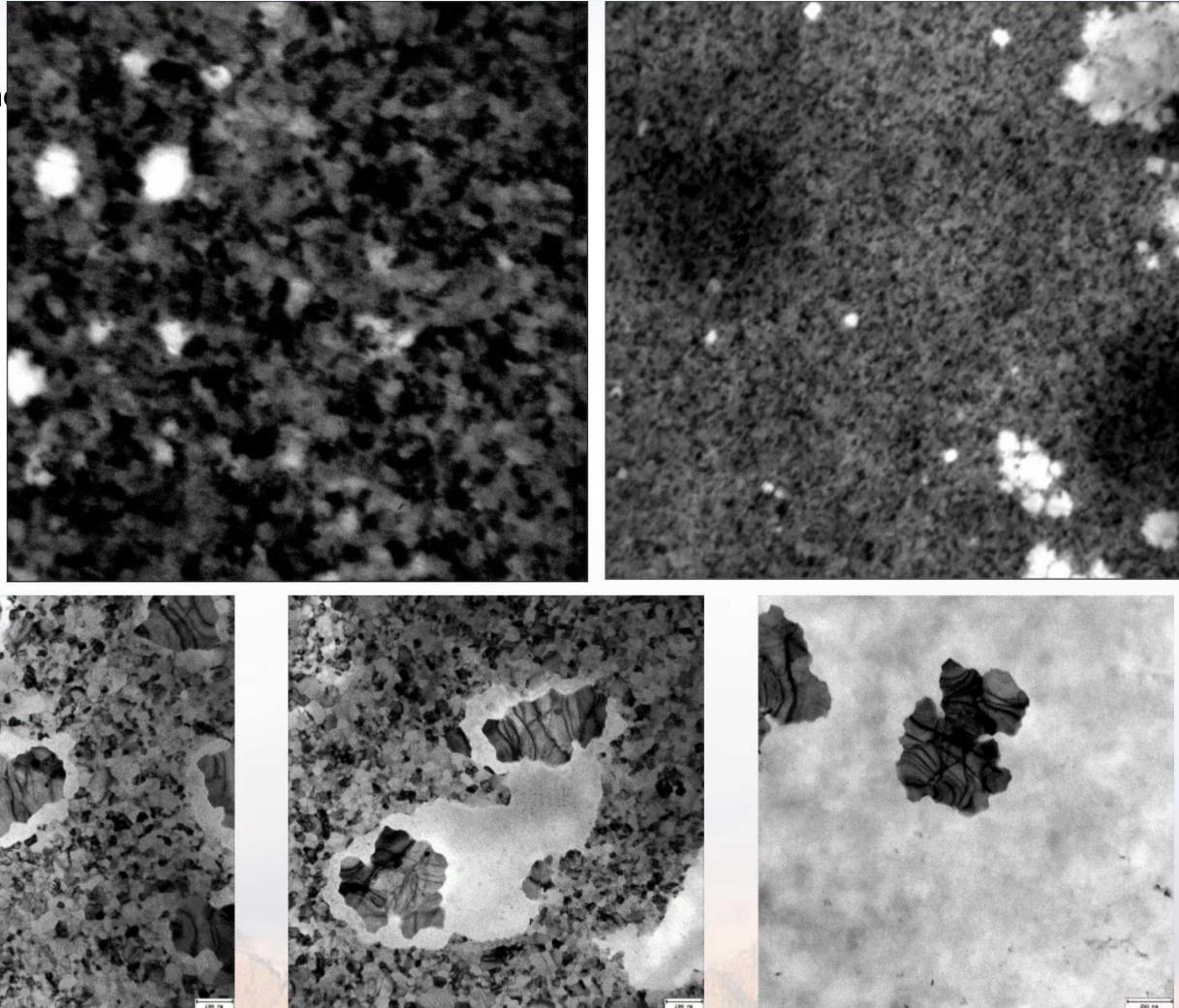
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Can We Gain Insight into the Corrosion Process through *In situ* TEM?

Contributors: D. Gross, J. Kacher, I.M. Robertson & Protochips, Inc.

Microfluidic Stage

- Mixing of two or more channels
- Continuous observation of the reaction channel



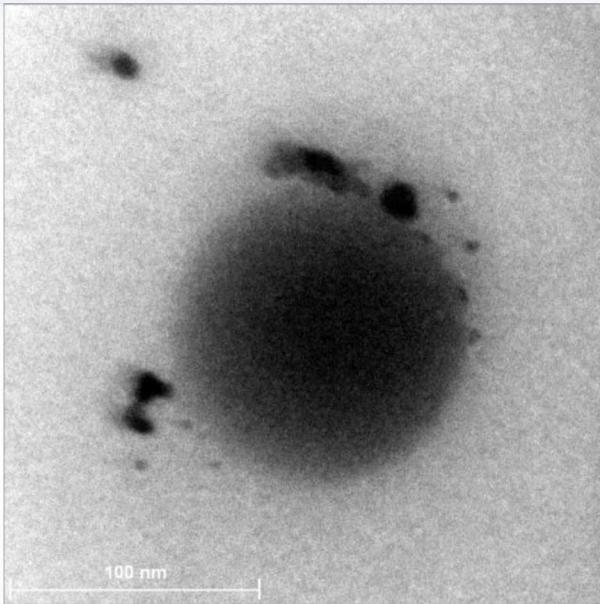
Pitting mechanisms during dilute flow of acetic acid over 99.95% nc-PLD Fe involves many grains.
Large grains resulting from annealing appear more corrosion tolerant

Other Fun Uses of Microfluidic Cell

Protocell Drug Delivery

S. Hoppe,
E. Carnes,
J. Brinker

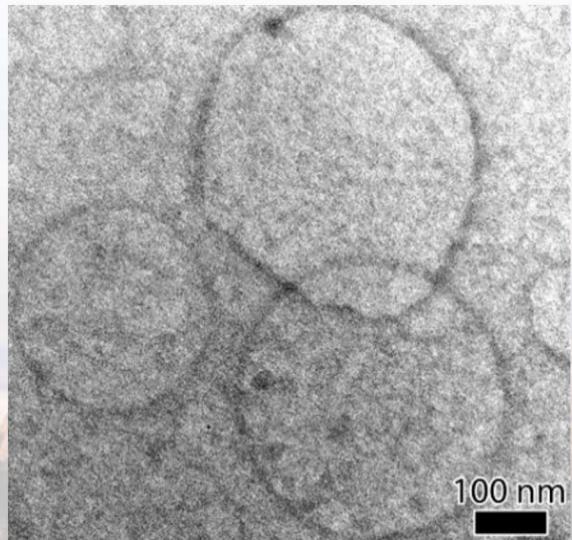
Liposome
encapsulated
Silica destroyed
by the electron
beam



Liposomes in Water

S. Hoppe,
D. Sasaki

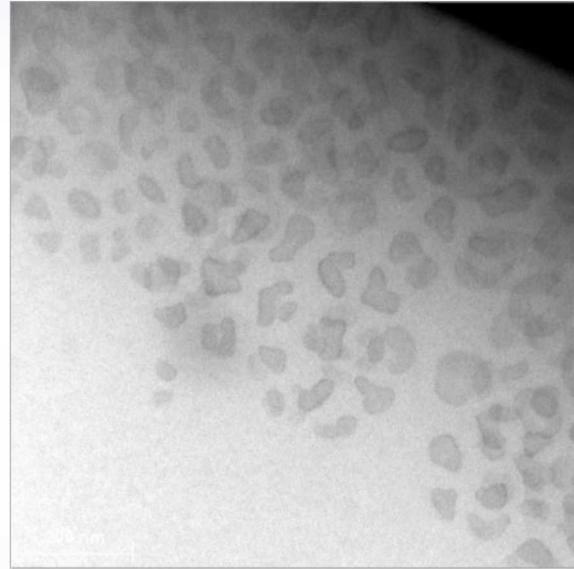
Liposomes
imaged in
flowing aqueous
channel



BSA Crystallization

S. Hoppe

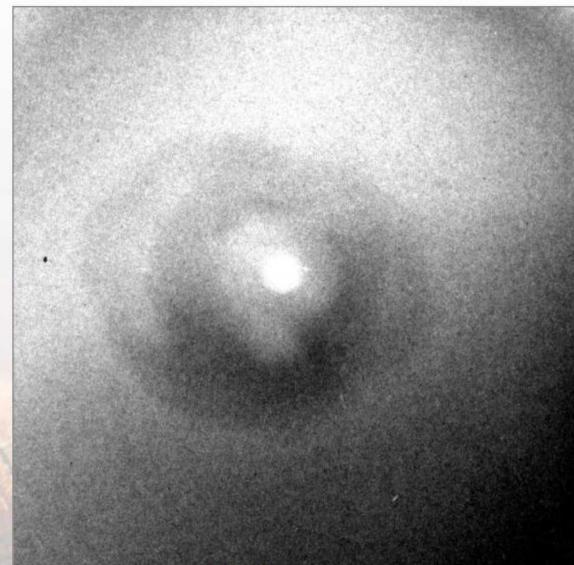
Crystallization of excess
Bovine Serum Albumen
during flow



La Structure Formation

S. Hoppe,
T. Nenoff

La
Nanostructure
form from LaCl_3
 H_2O in wet cell
due to beam
effects

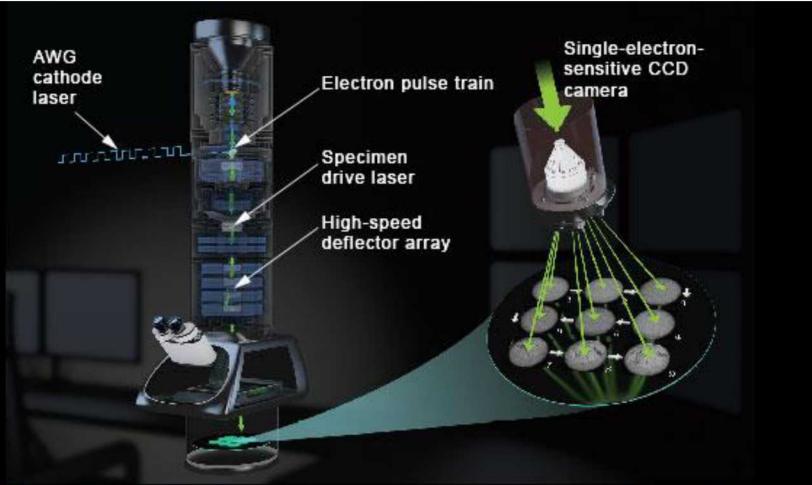


Can I³TEM and DTEM systems be combined?

LLNL DTEM



SNL I³TEM



Goal:

Combine the state-of-the-art in microscopy of DTEM and I³TEM to elucidate the response of extreme overlapping environments with adequate spatial and temporal resolution.



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Increasing Temporal Resolution

fs

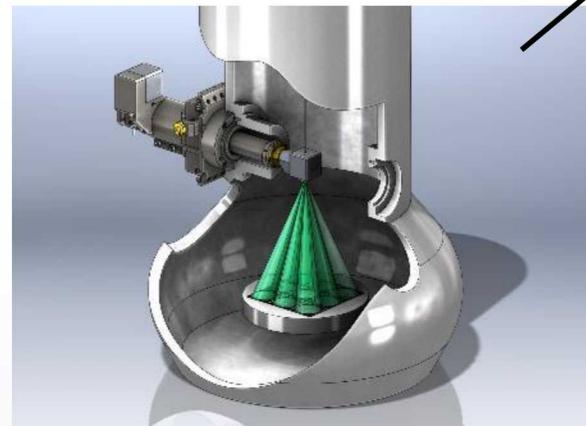
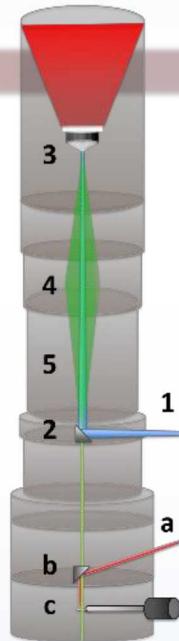
ps

ns

μ s

ms

s



■ DTEM

- Laser induced photoemission of electrons is needed to achieve sufficient current density to produce an image
- Provides nanosecond imaging of irreversible process

■ Deflector System

- Multiple images acquired on single frame
- Microsecond imaging possible
- Virtually no missing data (nanosecond gaps)

■ Standard 1K TVIPS camera

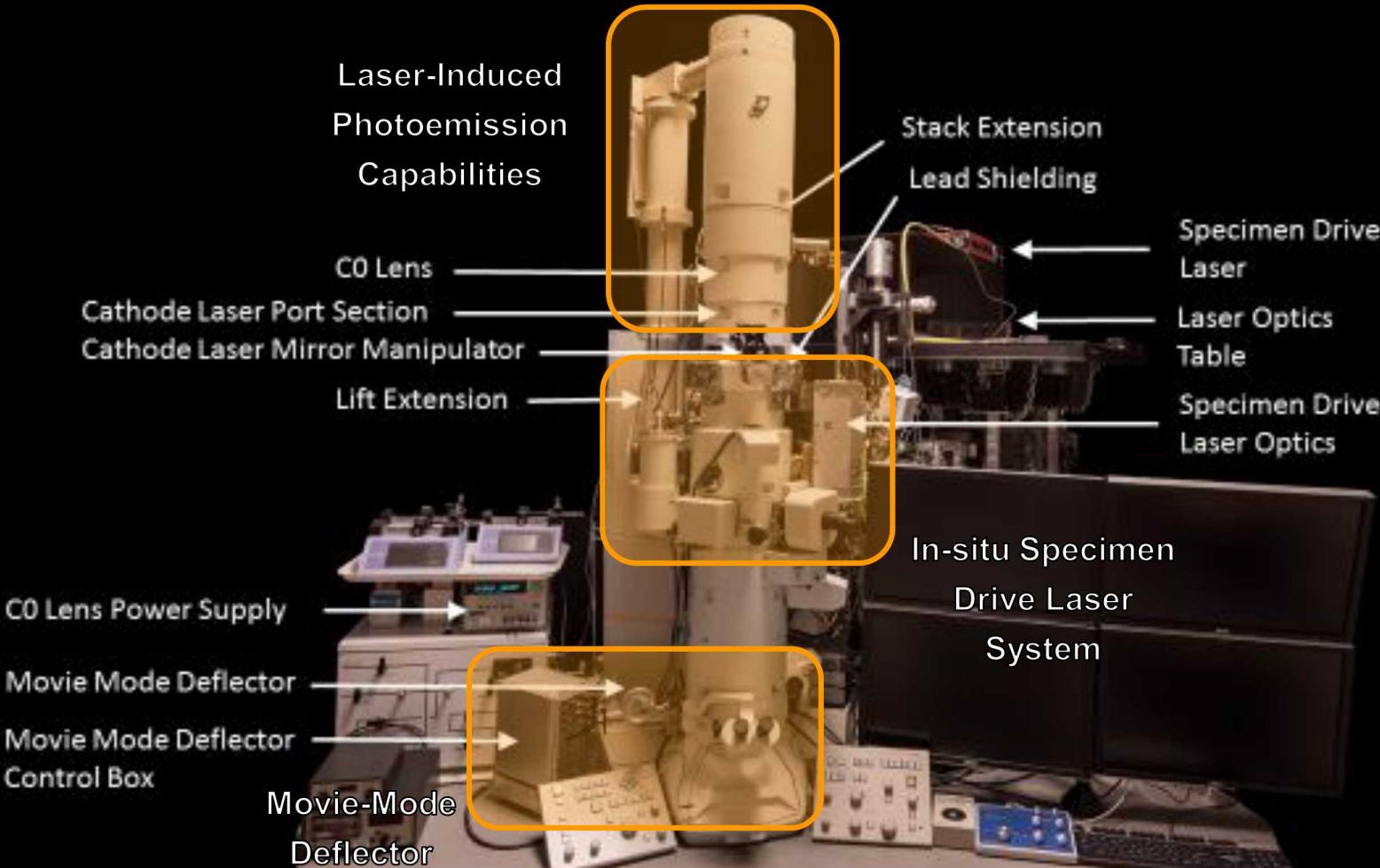
- Due to camera read out rate few images can be acquired
- 10-20fps maximum
- Missing data during camera readout



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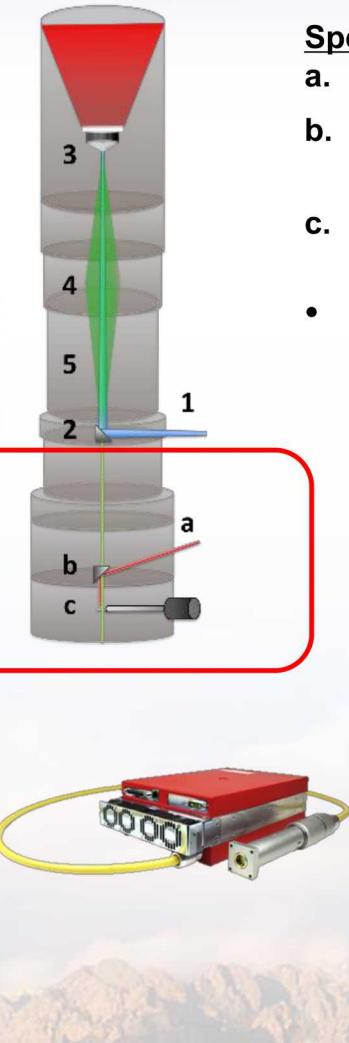
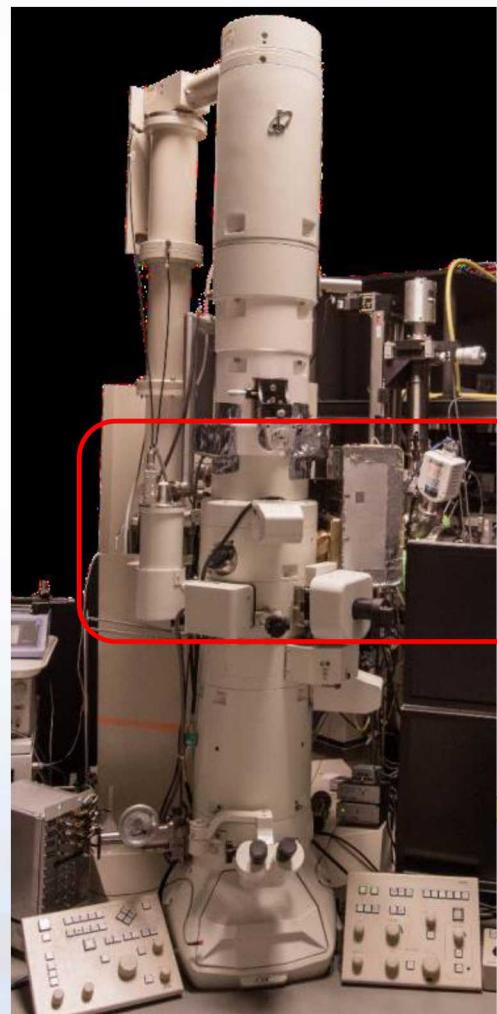


Current Status of Laser Addition and DTEM Conversion



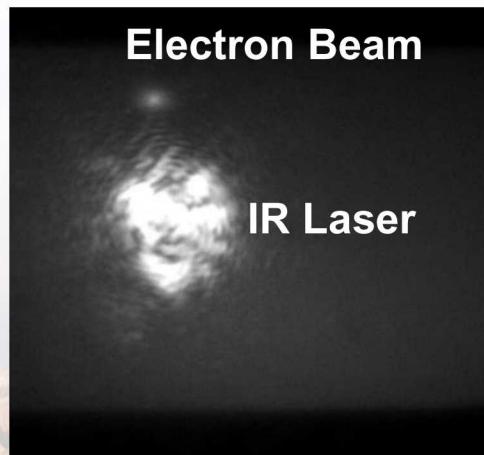
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In-situ Specimen Drive Laser System



Specimen Drive Laser

- a. Adjustable power 1064 nm infrared specimen (IR) drive laser
- b. IR laser is reflected directly onto the specimen with metal mirror
- c. Heat specimens in *in situ* holders, which otherwise would not be possible
 - Laser capabilities:
 - 2-20 Watts
 - Pulsed or continuous operation
 - 50 μ m diameter spot size
 - Positioning mirror, which can be used during laser operation



Laser Alignment TEM Holder

- Phosphor screen
- Borescope
- CCD camera
- Precise alignment of the laser to the electron beam

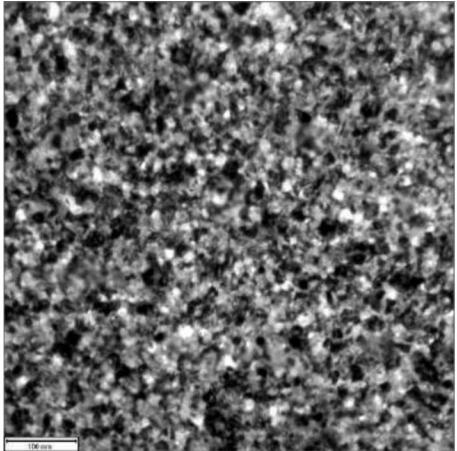


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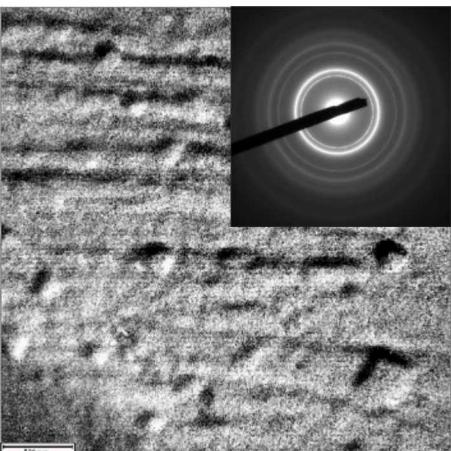
Initial Laser Heating Observations

Collaborator: P. Price, C.M. Barr, D. Adams, M. Abere

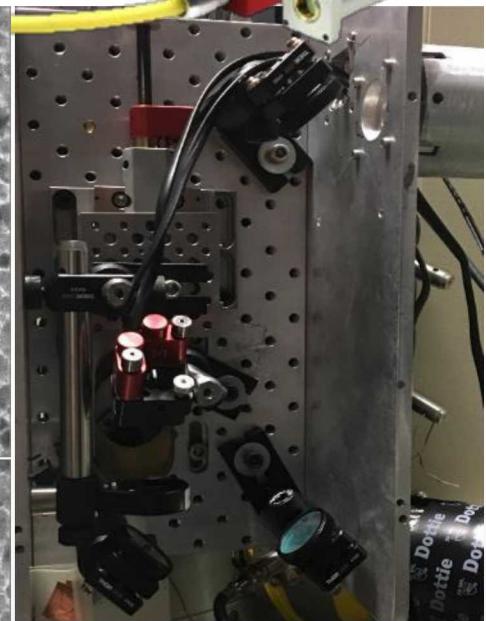
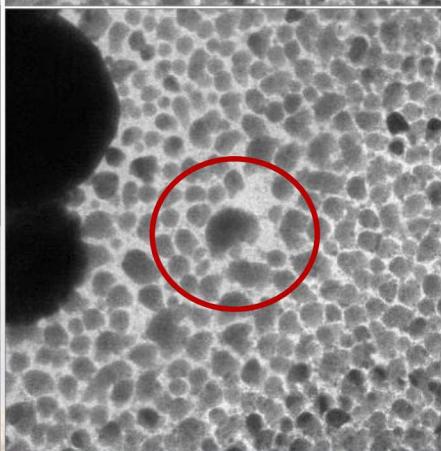
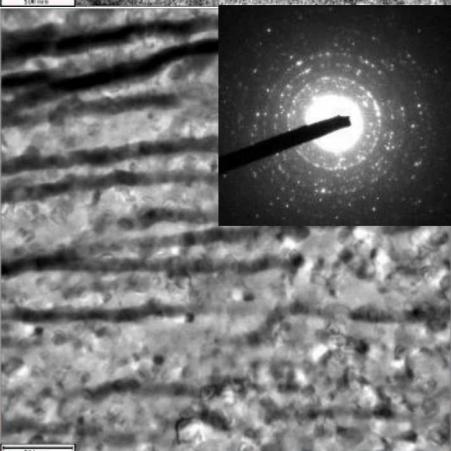
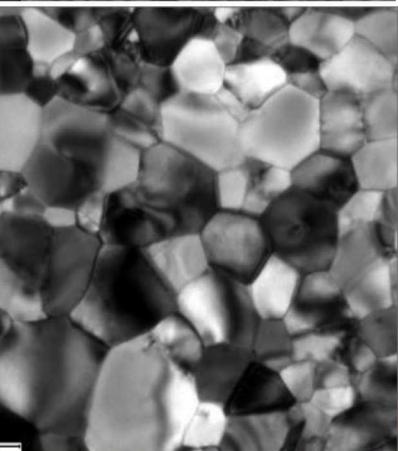
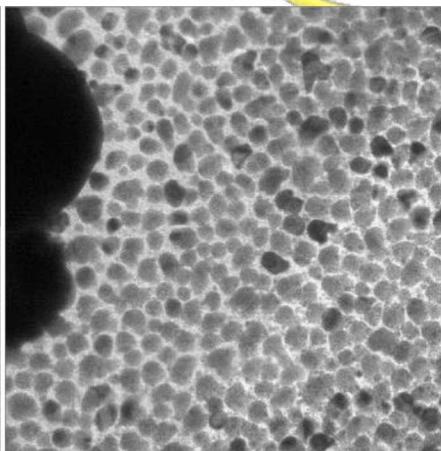
Pt Grain Growth



Reactive Multilayer Films



Nanoparticle Sintering



We can now introduce rapid thermal heating with
any TEM stage or ion beam conditions

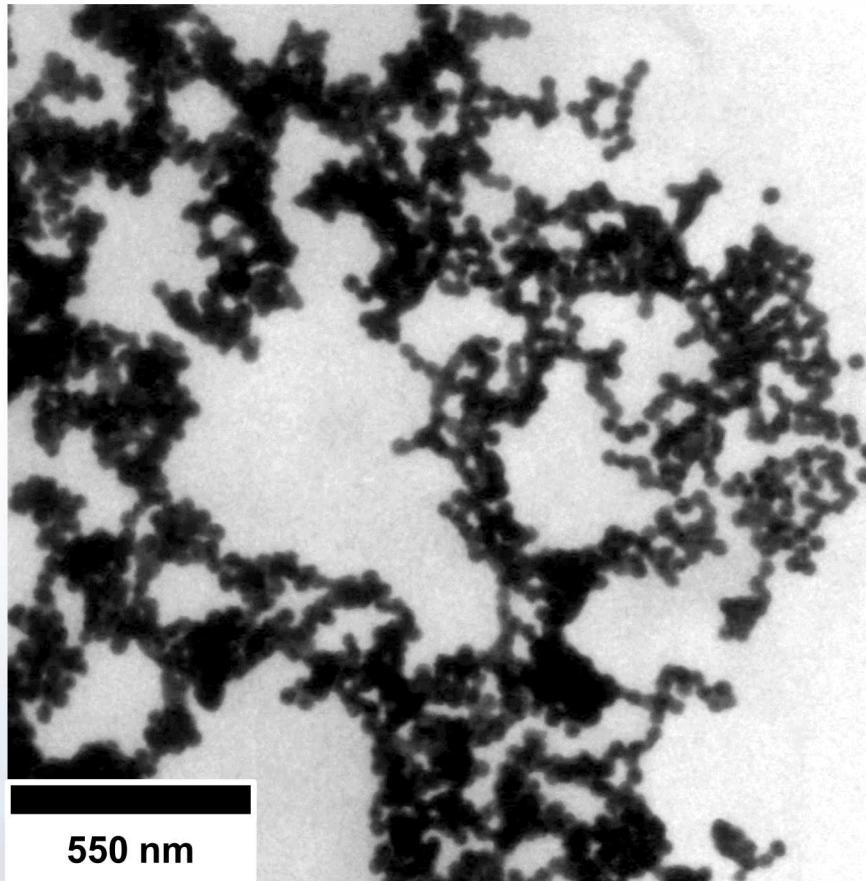


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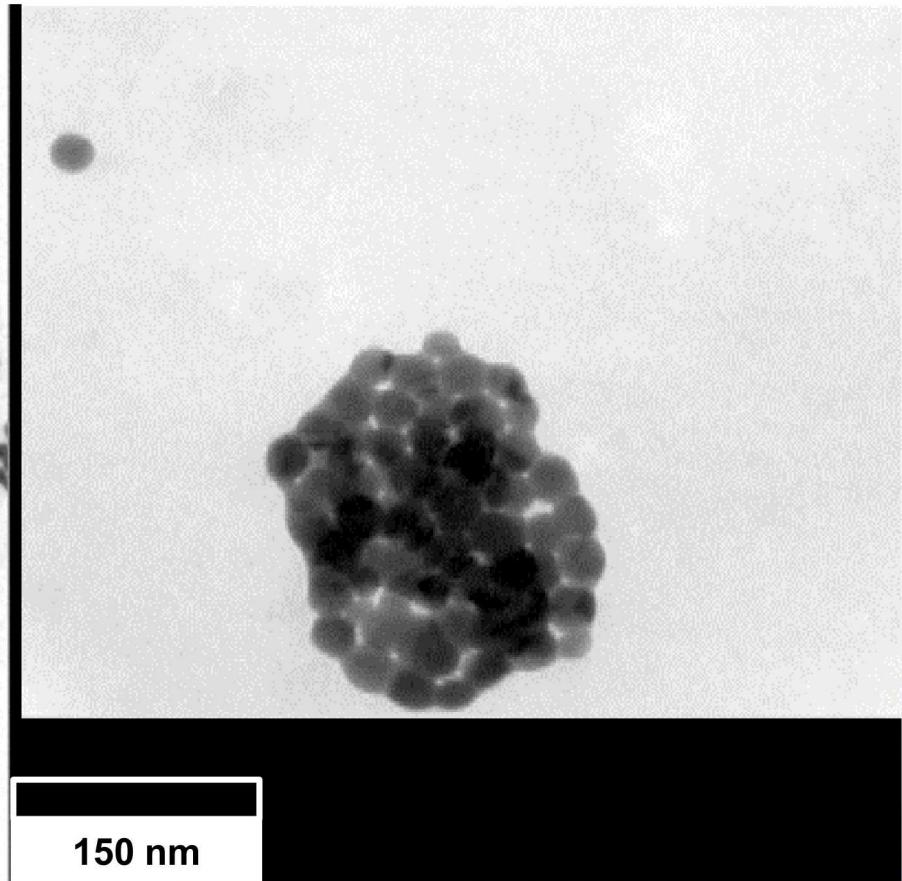


Complex Interaction Au NPs Exposed to Laser Irradiation

Contributors: P. Price, L. Treadwell, A. Cook



Speed = 2.5x



A Complex Combination of Sintering, Reactions, and Ablation Occurs

μ s Resolution with a Standard Camera

Collaborator: P. Price, A. Monterrosa, D. Adams, M. Abere, & IDES Inc.

fs

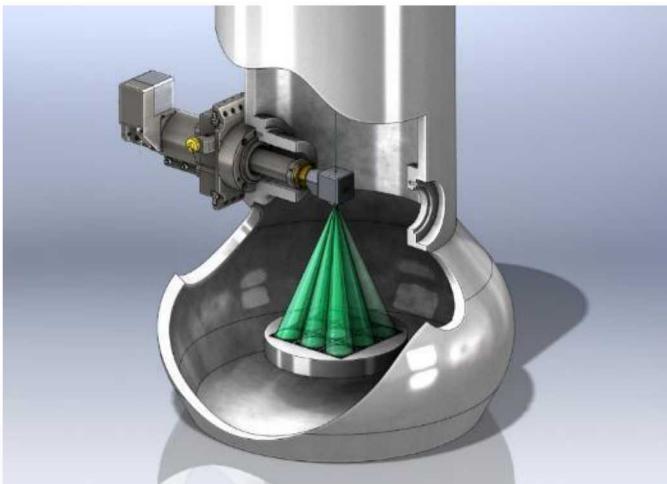
ps

ns

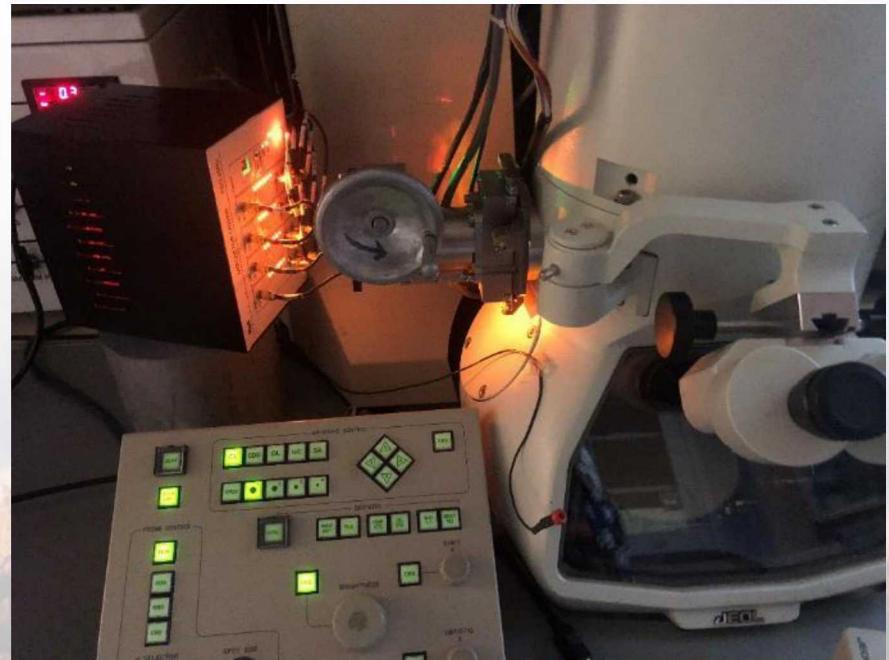
μ s

ms

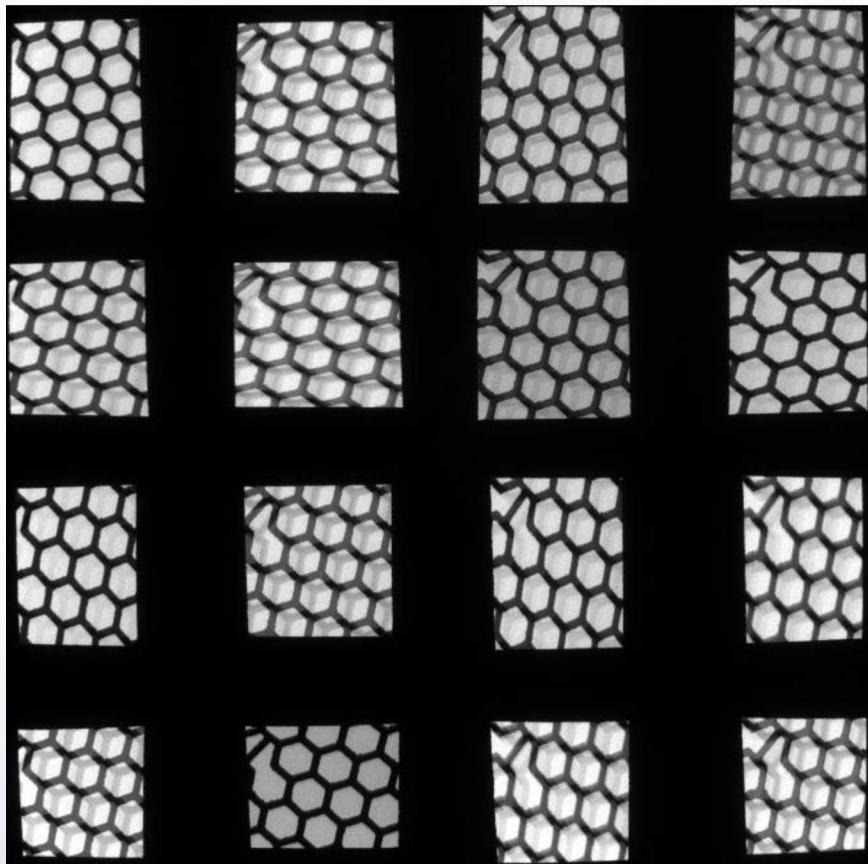
s



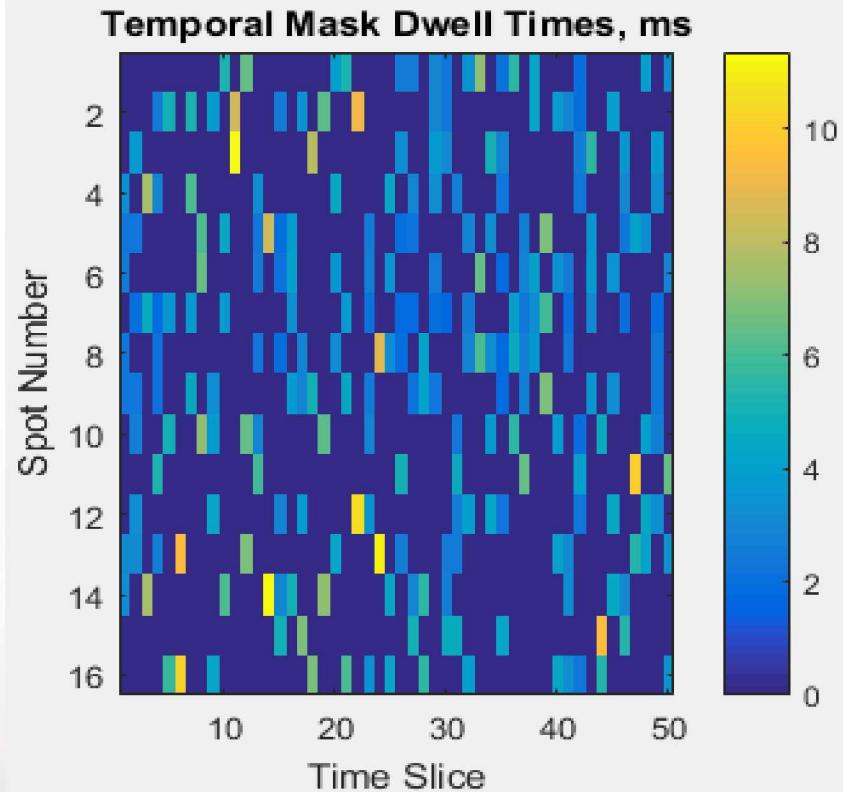
- Electrostatic deflection of electrons
- 4, 9, or 16 images per frame, spread over a large camera
- Any exposure time up to the limits of the camera
 - Ultimate limit is beam current/brightness



Movie Mode & Temporal Compressive Sensing



Up to 100 exposures can be acquired on a single camera frame giving μs temporal resolution



- Electron intensity of a single exposure is randomly distributed to multiple images within a single frame
- Record of random mask used to distribute exposure intensity is later used to deconvolute images

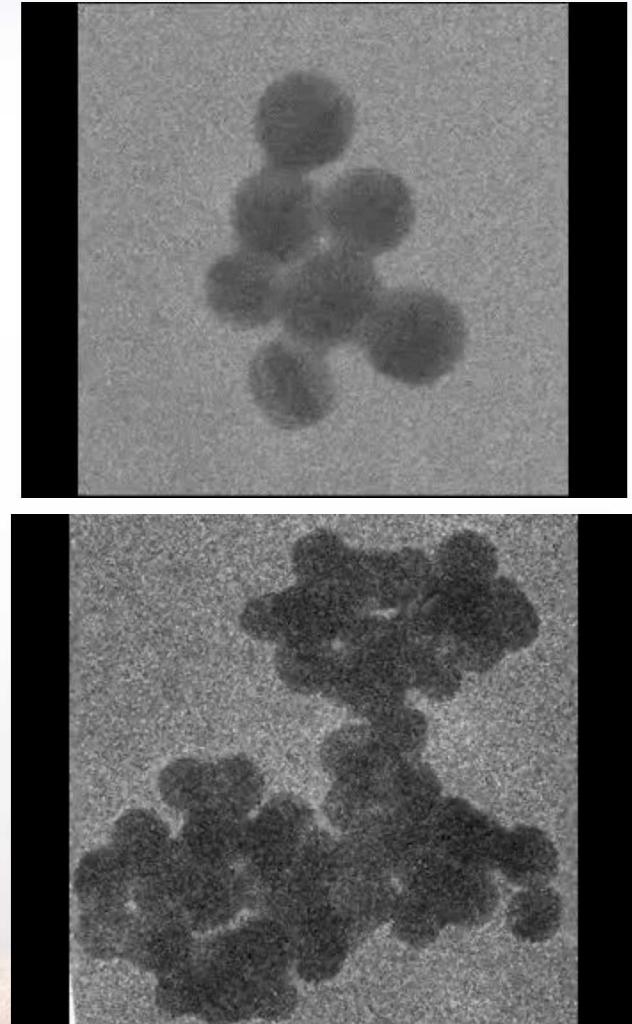
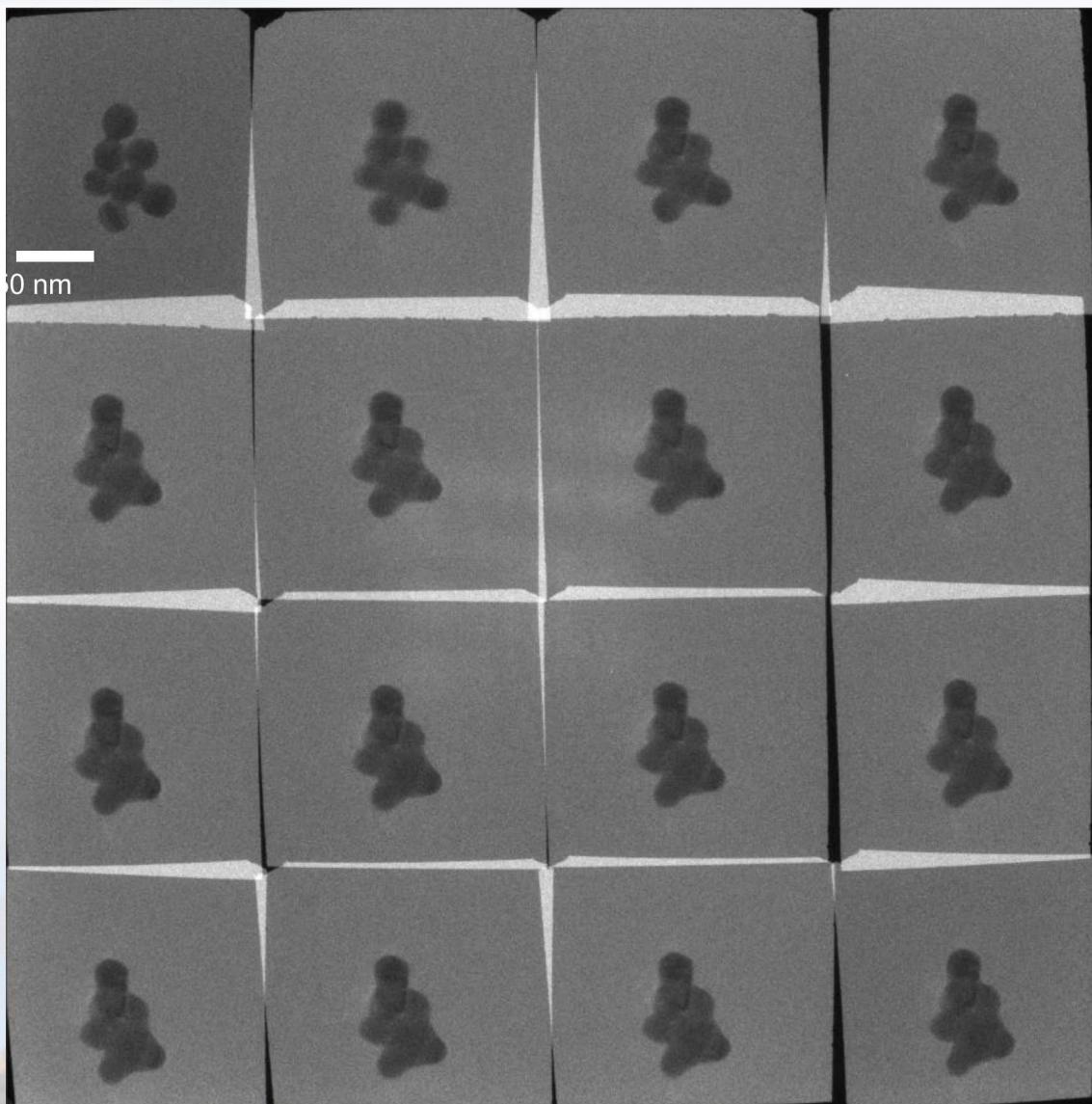


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1-to-1 Frame Capture (<5 ms per frame) Sintering of 20 nm Au Nanoparticles

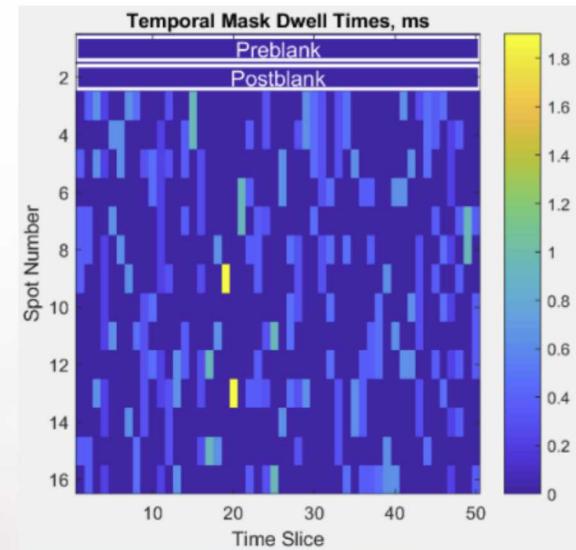
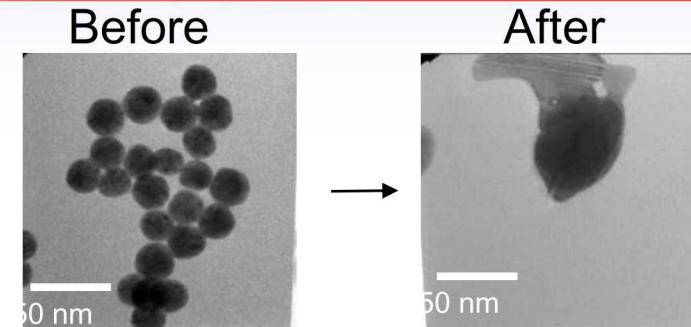
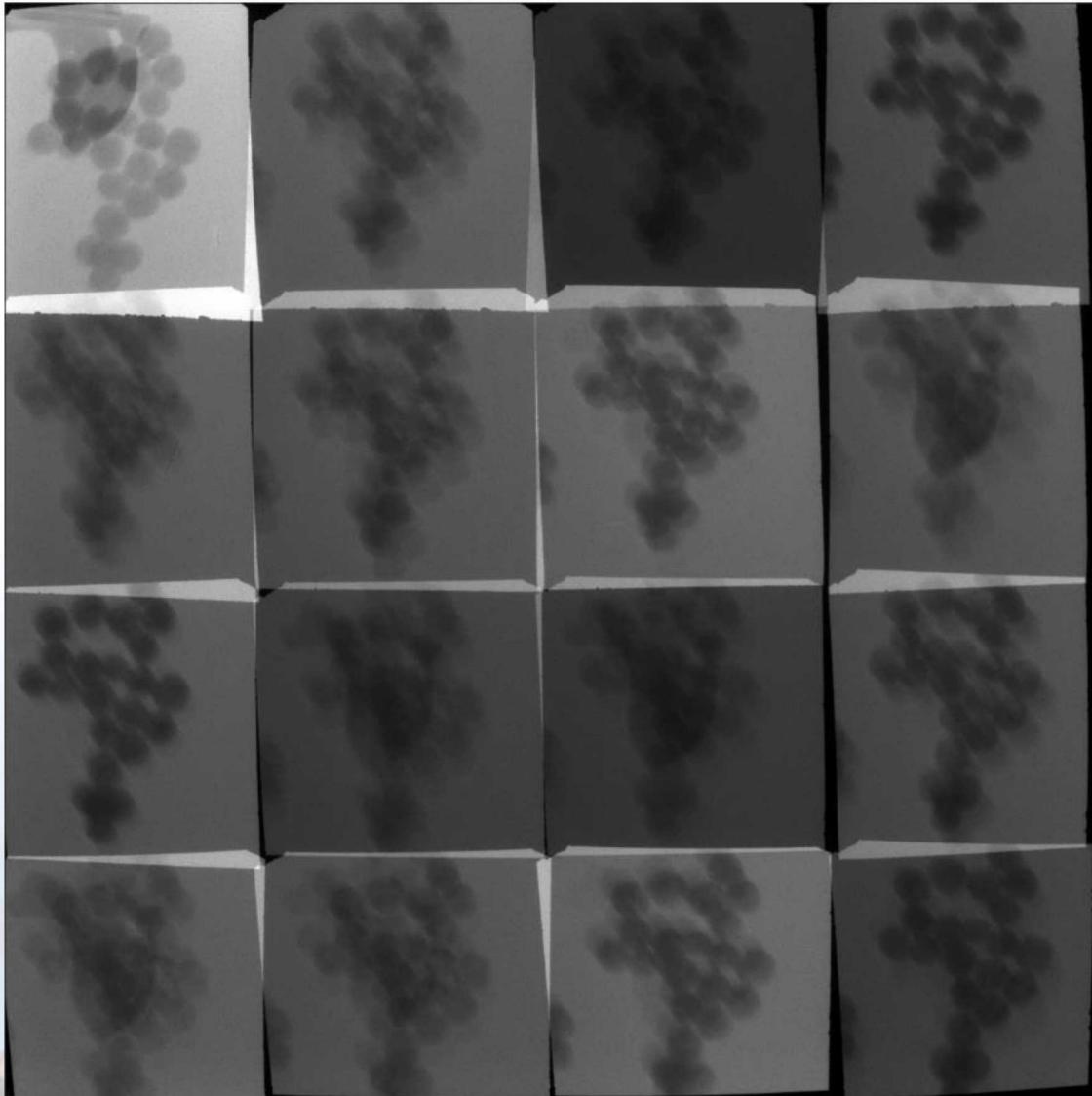
Collaborator: P. Price, A. Monterrosa, & IDES Inc.



16 frames captured with <5 ms
exposure per frame

Temporal Compressive Sensing to Improve Temporal Resolution

Collaborator: P. Price, A. Monterrosa, & IDES Inc.

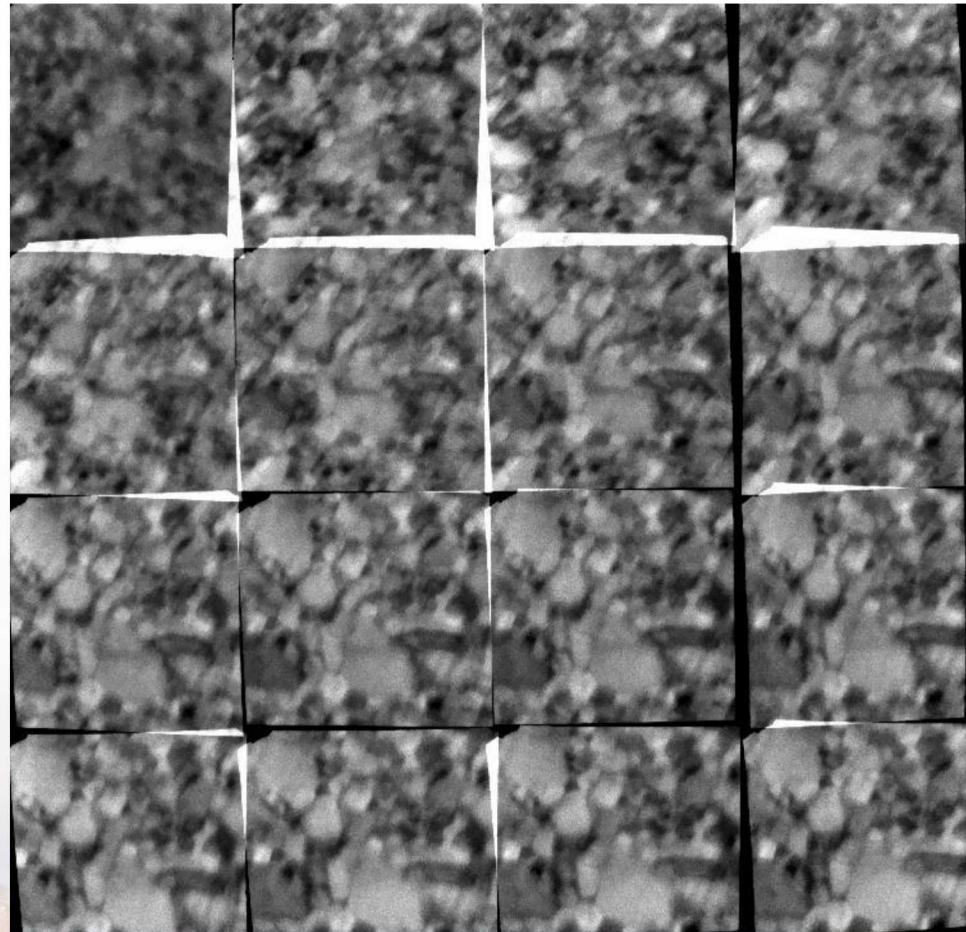
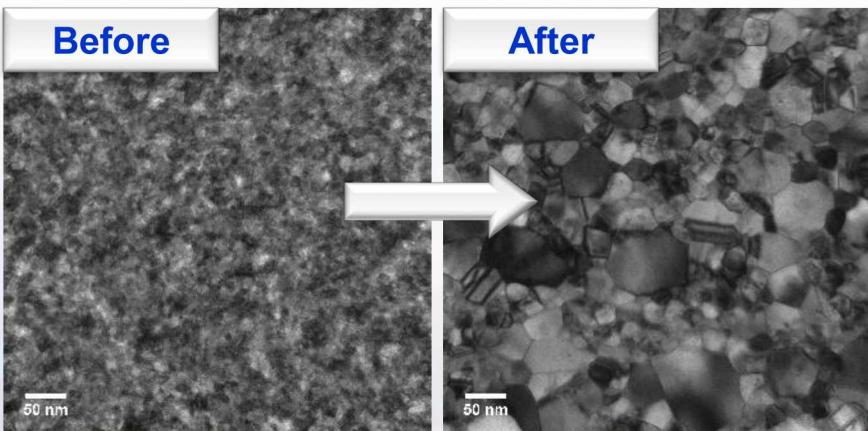


A pseudorandom exposure pattern can produce more than 16 frames within the same exposure time

Motivation: In-situ Microstructure Evolution

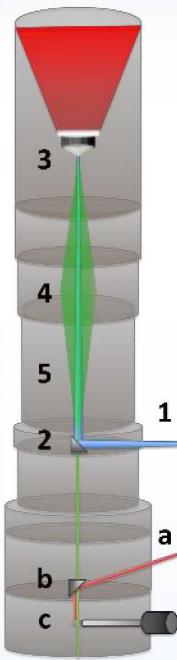
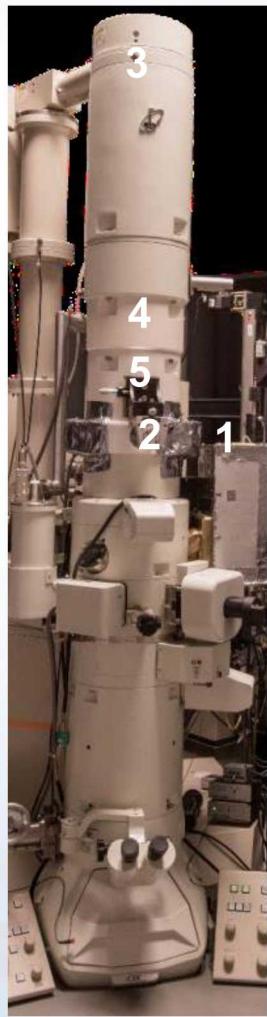
- In-situ TEM images of IR laser driven grain growth in Pt foil
- Characterize grain boundary and grain evolution
- Rapid heating & cooling controlled by specimen drive laser

Deflector System: Evolution of Pt microstructure with ~10ms exposures shown on the right



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Conversion of a Standard JEOL 2100 TEM to DTEM: Increase Current Density



C₀ Lens



Drift Section



UV Laser

A standard LaB₆ TEM has on average 1 or 2 electrons in the column at a given time!

Laser induced photoemission of electrons can increase nanosecond electron current by 6-8 orders of magnitude

DTEM Development

1. Ultraviolet laser and optics system capable of producing nanosecond pulses
2. Adjustable molybdenum mirror assembly to reflect the UV laser up the column
3. Tantalum cathode disc filament
4. Addition of a C₀ lens and power supply to gather electrons increasing current to the specimen
5. Addition of a drift section to condense electrons from the C₀ lens
6. Lead shielding as needed to ensure safe operation of the instrument

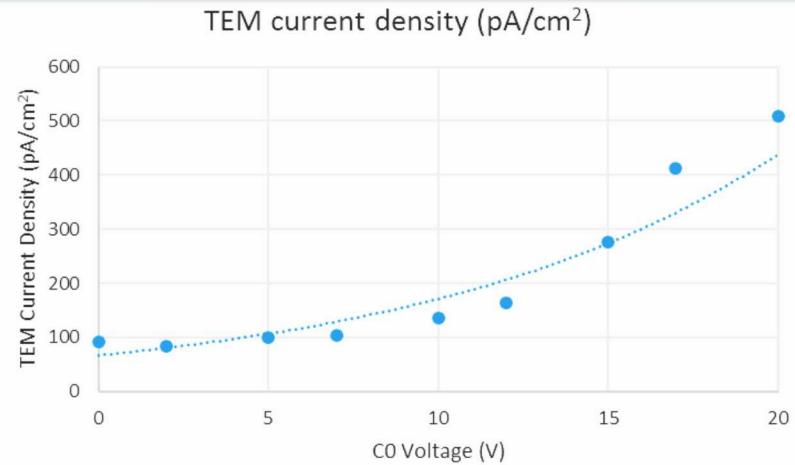


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Increased Current Density & added 18" to TEM Column



Addition of C_0 lens and drift section give a 5X increase in current density



- Disc cathode produces wider distribution of electrons than LaB_6
- Current density can be increased by adding C_0 lens to condense electrons to a smaller probe
- Strength of C_0 lens is controlled by external adjustable power supply
 - Trade off between current density and resolution
- Drift section gives more time for electrons to condense after the C_0 lens. C_0 can be weaker

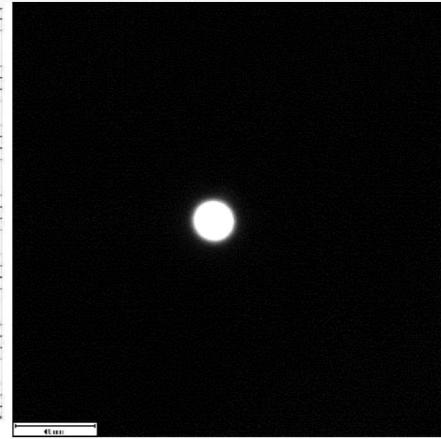
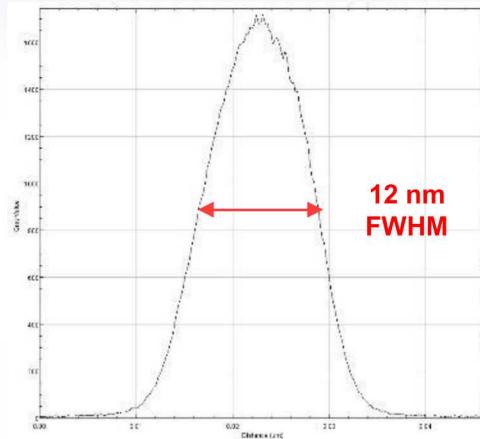


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Tantalum Filament Exchange

■ Changes with C_0 lens setting of 0V

- 50% reduction in electron
 - LaB_6 ~ 50 pA/cm²
 - Ta ~ 30 pA/cm²
- Higher beam current at from source
 - LaB_6 ~ 7 μA
 - Ta ~ 23 μA
- Increase in minimum spot size for precession
 - LaB_6 ~ 8 nm FWHM
 - Ta ~ 12 nm FWHM

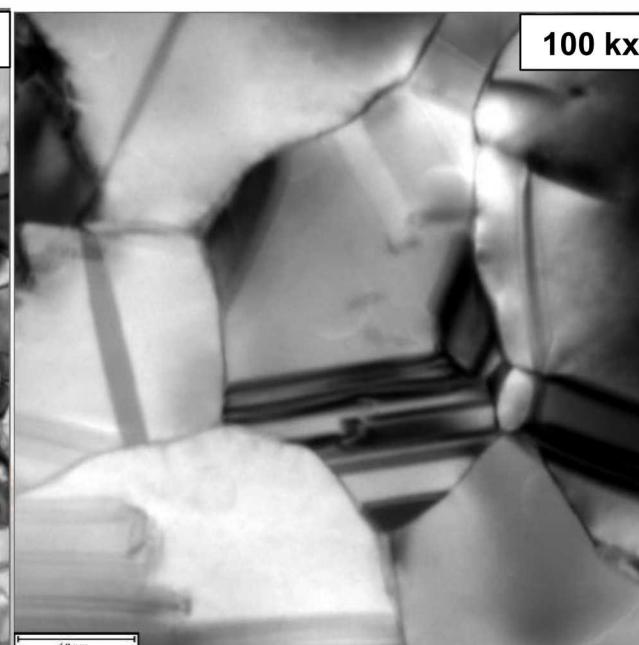
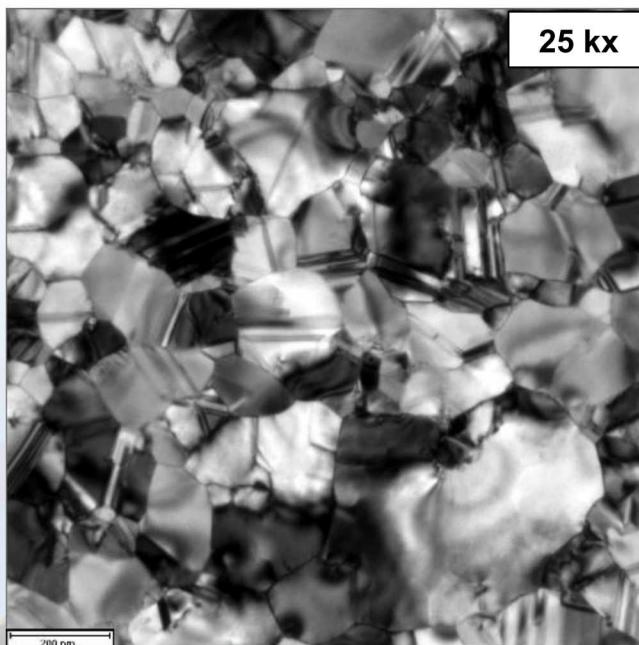


Above:

Smallest achievable spot size for precession with Ta cathode

Left:

Bright field TEM images of nanocrystalline gold taken with Ta filament



Easily switch between DTEM and thermal emission with good resolution in minutes!

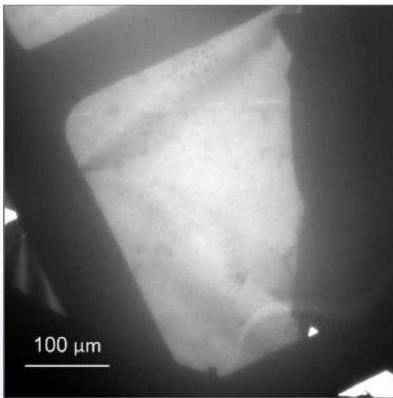
Filament exchange in as little as 90 min.



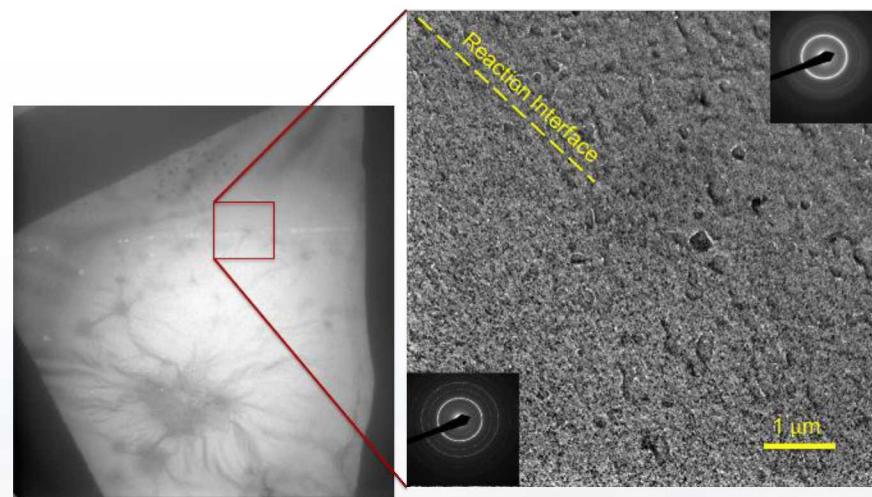
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DTEM of Reactive Multilayers

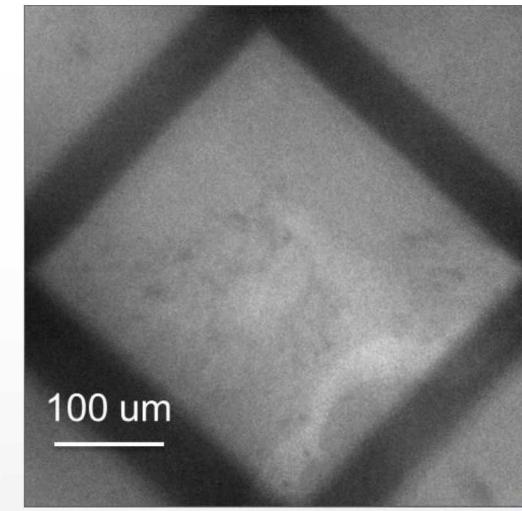
Reactive multilayers provide an excellent example of the capabilities of DTEM. Al/Co multilayer samples are ignited by the IR laser, and convert to a CoAl phase. The reaction front propagates across the sample at ~ 10 m/s. With a fast enough time resolution this wavefront can be captured.



Al/Co
multilayer
sample **before**
IR laser shot



Al/Co multilayer sample **after IR laser shot**
and closeup of reaction interface



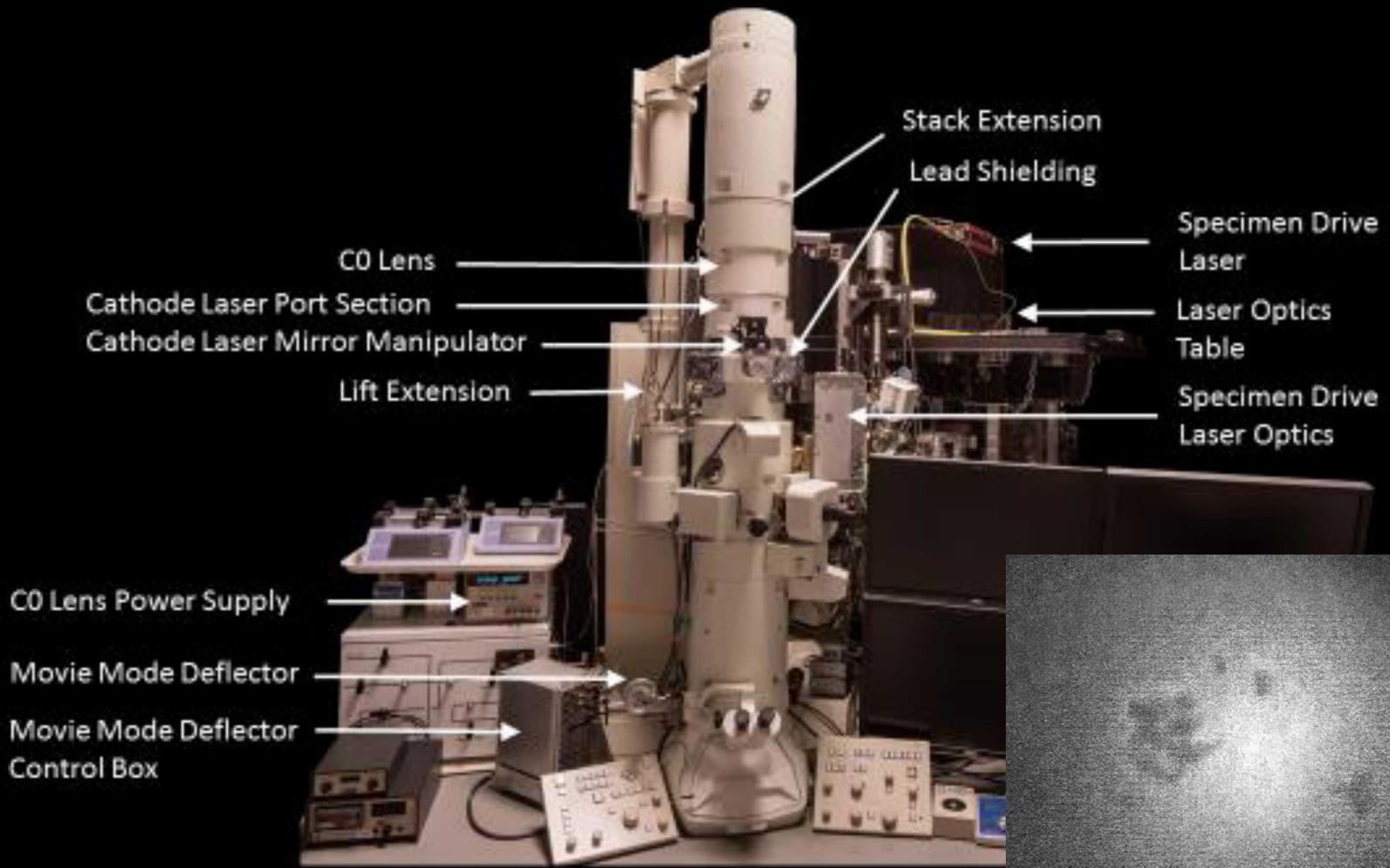
Single shot DTEM of
unreacted Al/Co
multilayer sample



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Current Status of DTEM Conversion

Collaborator: P. Price, A. Monterrosa, C.M. Barr, D. Adams, M. Abere, & IDES Inc.



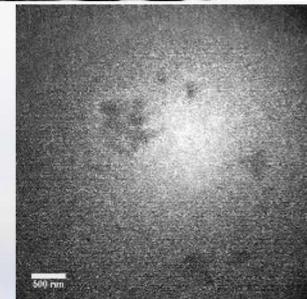
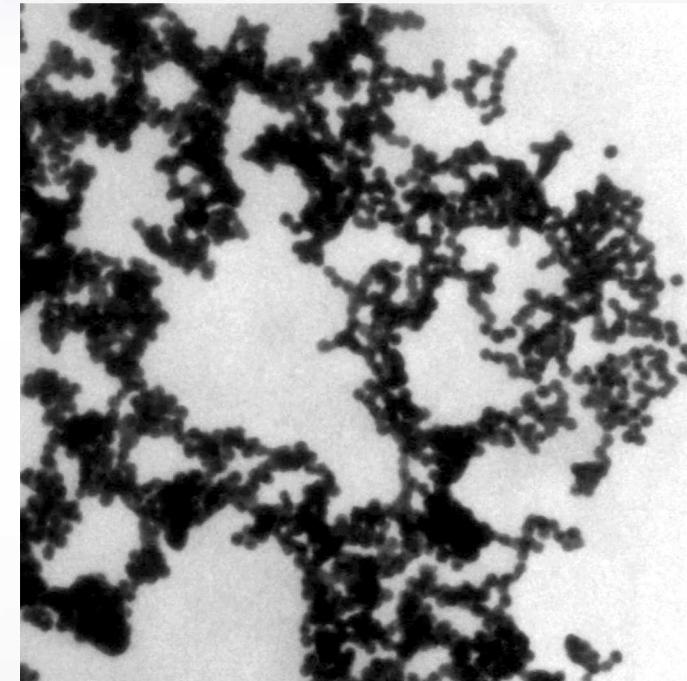
- 266 nm UV laser induced photoemission has been achieved!
- 6 ns single-shot DTEM image of P47

Unconventional *In situ* Microscopy Creates a wealth of Possibilities

- Fundamental TEM modifications for DTEM, movie mode, and compressive sensing have progressed.
- Maintained functionality of the TEM using LaB₆ thermal emission with minimal impact
- Possible to switch between LaB6 and DTEM in just a few hours
- Compressive sensing permits microsecond temporal resolution
- Laser induced photoemission of electrons has been achieved with in single shot 6 ns temporal resolution
- Advanced temporal resolution on the I³TEM combined with the wide range of available in-situ capacities provide a wealth of experimental control

Collaborators:

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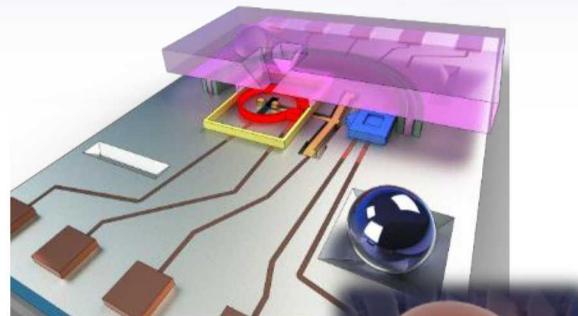
Sandia's USER Capabilities



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www.cint.lanl.gov

- Spring and Fall proposals for 18 months
- Rapid Access proposal anytime for 3 months



Core Facility - SNL

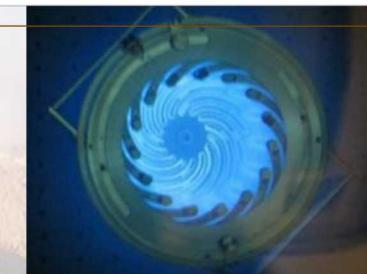
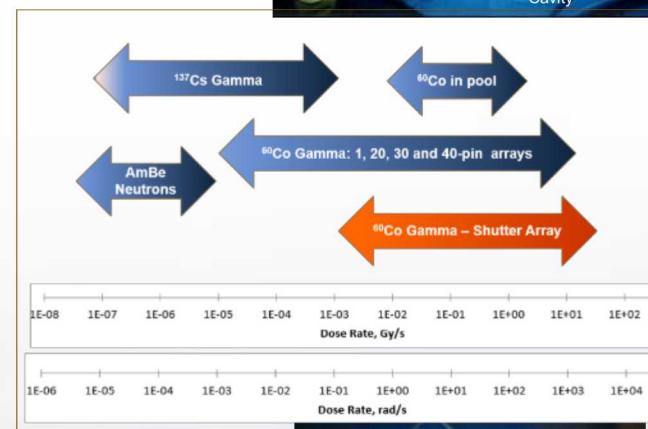
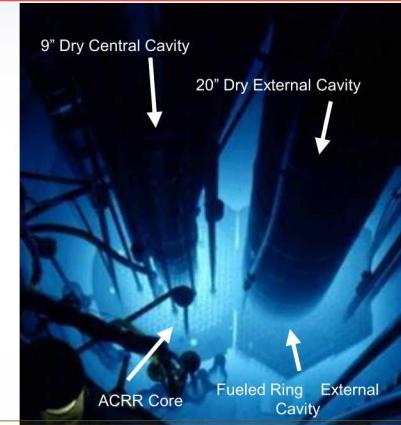


Gateway Facility - LANL



www.nsuf.inl.gov

- Three proposal a year for 9 months



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